

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/827,279	BEST, CHRISTOPHER B.	
		Examiner	Art Unit	Page 1 of 1
		Sebastiano Passaniti	3711	

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,198,062 A	03-1993	Chen, Archer C. C.	156/245
*	B	US-5,288,070 A	02-1994	Chen, Archer C. C.	473/331
*	C	US-5,398,929 A	03-1995	Kitaichi, Hideo	473/329
*	D	US-5,403,007 A	04-1995	Chen, Archer C. C.	473/342
*	E	US-5,431,396 A	07-1995	Shieh, Tien W.	473/329
*	F	US-5,524,331 A	06-1996	Pond, Brian R.	29/527.4
*	G	US-5,772,527 A	06-1998	Liu, Jung Ming	473/324
*	H	US-6,042,486 A	03-2000	Gallagher, Kenny A.	473/329
*	I	US-6,095,931 A	08-2000	Hettinger et al.	473/341
*	J	US-6,743,117 B2	06-2004	Gilbert, Peter J.	473/332
*	K	US-7,070,513 B2	07-2006	Takeda et al.	473/329
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.